

TC74HC4002AP, TC74HC4002AF

Dual 4-Input NOR Gate

The TC74HC4002A is a high speed CMOS 4-INPUT NOR GATE fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

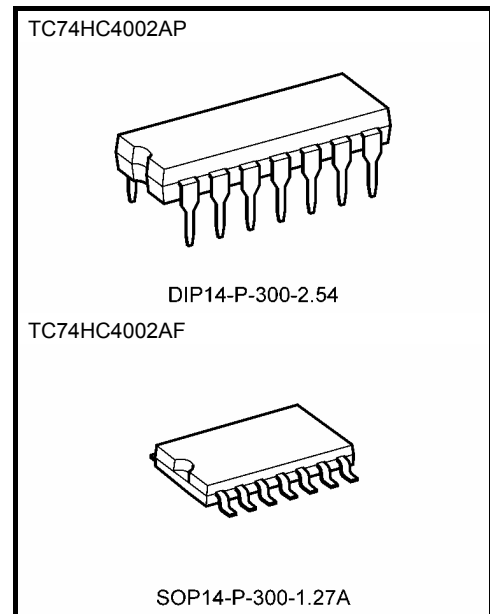
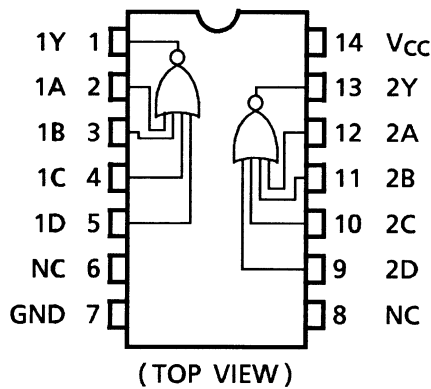
The internal circuit is composed of 3 stages including a buffer output, which provide high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

- High speed: $t_{pd} = 10 \text{ ns}$ (typ.) at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 1 \mu\text{A}$ (max) at $T_a = 25^\circ\text{C}$
- High noise immunity: $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: $|I_{OH}| = I_{OL} = 4 \text{ mA}$ (min)
- Balanced propagation delays: $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range: $V_{CC} \text{ (opr)} = 2\sim 6 \text{ V}$
- Pin and function compatible with 4002B.

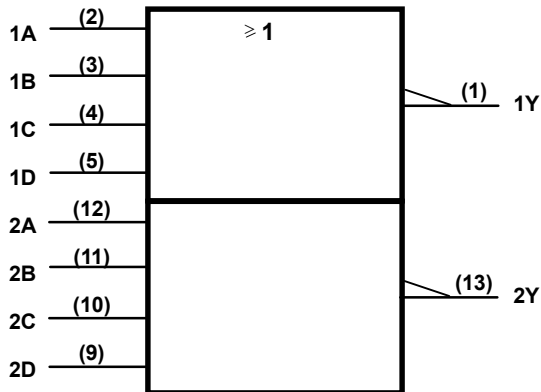
Pin Assignment



Weight

DIP14-P-300-2.54	: 0.96 g (typ.)
SOP14-P-300-1.27A	: 0.18 g (typ.)

IEC Logic Symbol



Truth Table

A	B	C	D	Y
H	X	X	X	L
X	H	X	X	L
X	X	H	X	L
X	X	X	H	L
L	L	L	L	H

X: Don't care

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	-0.5~7	V
DC input voltage	V_{IN}	-0.5~ $V_{CC} + 0.5$	V
DC output voltage	V_{OUT}	-0.5~ $V_{CC} + 0.5$	V
Input diode current	I_{IK}	± 20	mA
Output diode current	I_{OK}	± 20	mA
DC output current	I_{OUT}	± 25	mA
DC V_{CC} /ground current	I_{CC}	± 50	mA
Power dissipation	P_D	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T_{stg}	-65~150	$^{\circ}C$

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of $T_a = -40$ to $65^{\circ}C$. From $T_a = 65$ to $85^{\circ}C$ a derating factor of -10 mW/ $^{\circ}C$ shall be applied until 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2~6	V
Input voltage	V_{IN}	0~ V_{CC}	V
Output voltage	V_{OUT}	0~ V_{CC}	V
Operating temperature	T_{opr}	-40~85	°C
Input rise and fall time	t_r, t_f	0~1000 ($V_{CC} = 2.0$ V) 0~500 ($V_{CC} = 4.5$ V) 0~400 ($V_{CC} = 6.0$ V)	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device.
Unused inputs must be tied to either V_{CC} or GND.

Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition	V_{CC} (V)	$T_a = 25^\circ\text{C}$			$T_a = -40\sim 85^\circ\text{C}$		Unit	
				Min	Typ.	Max	Min	Max		
High-level input voltage	V_{IH}	—	2.0	1.50	—	—	1.50	—	V	
			4.5	3.15	—	—	3.15	—		
			6.0	4.20	—	—	4.20	—		
Low-level input voltage	V_{IL}	—	2.0	—	—	0.50	—	0.50	V	
			4.5	—	—	1.35	—	1.35		
			6.0	—	—	1.80	—	1.80		
High-level output voltage	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -20 \mu\text{A}$	2.0	1.9	2.0	—	1.9	—	V
			$I_{OH} = -4 \text{ mA}$	4.5	4.4	4.5	—	4.4	—	
			$I_{OH} = -5.2 \text{ mA}$	6.0	5.9	6.0	—	5.9	—	
Low-level output voltage	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 20 \mu\text{A}$	2.0	—	0.0	0.1	—	0.1	V
			$I_{OL} = 4 \text{ mA}$	4.5	—	0.0	0.1	—	0.1	
			$I_{OL} = 5.2 \text{ mA}$	6.0	—	0.0	0.1	—	0.1	
Input leakage current	I_{IN}	$V_{IN} = V_{CC}$ or GND	6.0	—	—	± 0.1	—	± 1.0	μA	
Quiescent supply current	I_{CC}	$V_{IN} = V_{CC}$ or GND	6.0	—	—	1.0	—	10.0	μA	

AC Characteristics ($C_L = 15 \text{ pF}$, $V_{CC} = 5 \text{ V}$, $T_a = 25^\circ\text{C}$, input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time	t_{TLH}	—	—	4	8	ns
	t_{THL}					
Propagation delay time	t_{pLH}	—	—	10	17	ns
	t_{pHL}					

AC Characteristics ($C_L = 50 \text{ pF}$, input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition	V_{CC} (V)	$T_a = 25^\circ\text{C}$			$T_a = -40\sim 85^\circ\text{C}$		Unit
				Min	Typ.	Max	Min	Max	
Output transition time	t_{TLH} t_{THL}	—	2.0	—	30	75	—	95	ns
			4.5	—	8	15	—	19	
			6.0	—	7	13	—	16	
Propagation delay time	t_{pLH} t_{pHL}	—	2.0	—	40	100	—	125	ns
			4.5	—	13	20	—	25	
			6.0	—	11	17	—	21	
Input capacitance	C_{IN}	—	—	5	10	—	10	pF	
Power dissipation capacitance	C_{PD} (Note)	—	—	22	—	—	—	pF	

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2 \text{ (per gate)}$$

Package Dimensions

DIP14-P-300-2.54

Unit : mm



Weight: 0.96 g (typ.)

Package Dimensions

SOP14-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)

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20070701-EN GENERAL

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